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Monte Carlo Simulations for Silicon Detectors

Bridging the Gap between Detector Design and Prototype Testing

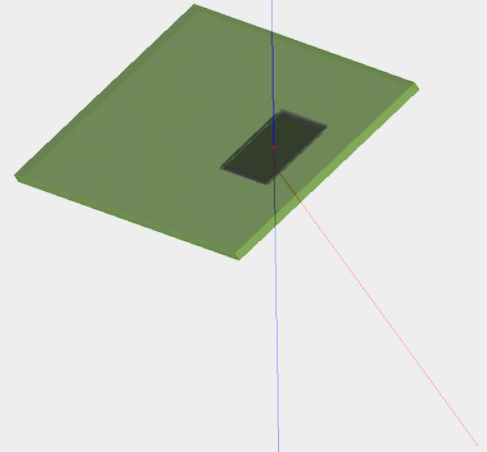
Simon Spannagel, CERN

CERN Detector Seminar

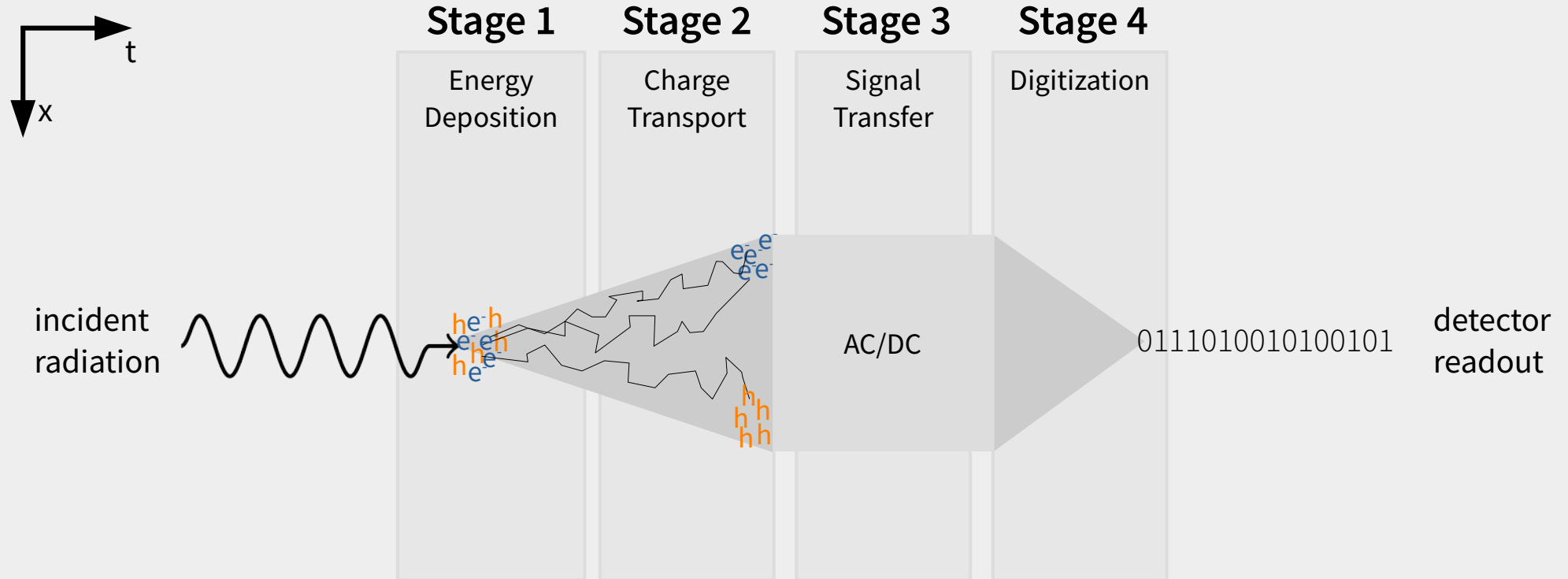
12 April 2019

Introduction

Particle Detection with Silicon Detectors

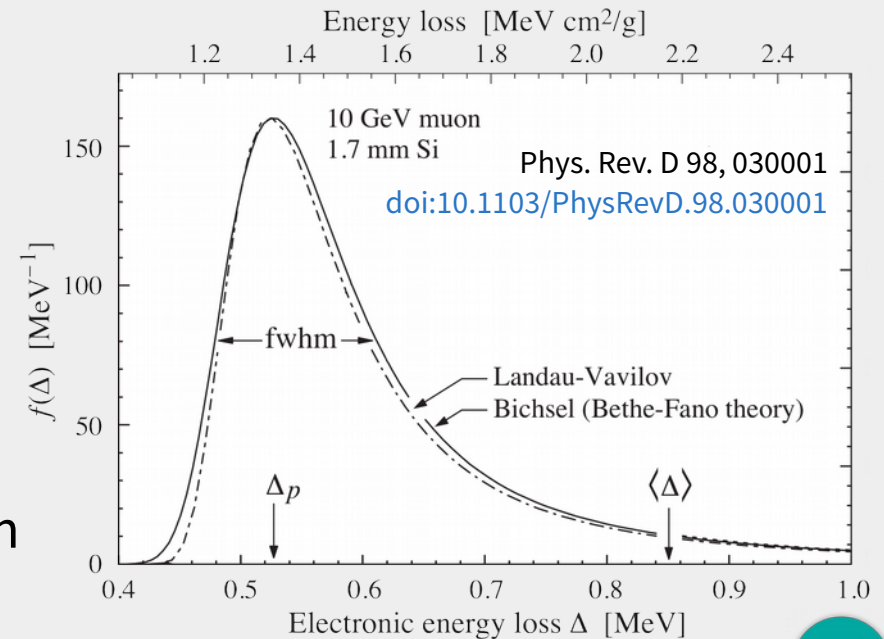


Recap: Particle Detection with Silicon Detectors



Stage 1 – Energy Deposition

- (heavy) charged particles:
Mean energy loss described by **Bethe Bloch** formula
- Strong fluctuations of energy loss: **Landau-Vavilov** distribution / **Bichsel** model
 - Varying number interactions
 - Varying energy transfer
 - Secondary particles (e.g. delta rays)
 - Most probable value < Mean
- Photons:
Photo effect, Compton effect, pair production



Stage 2 – Signal Formation

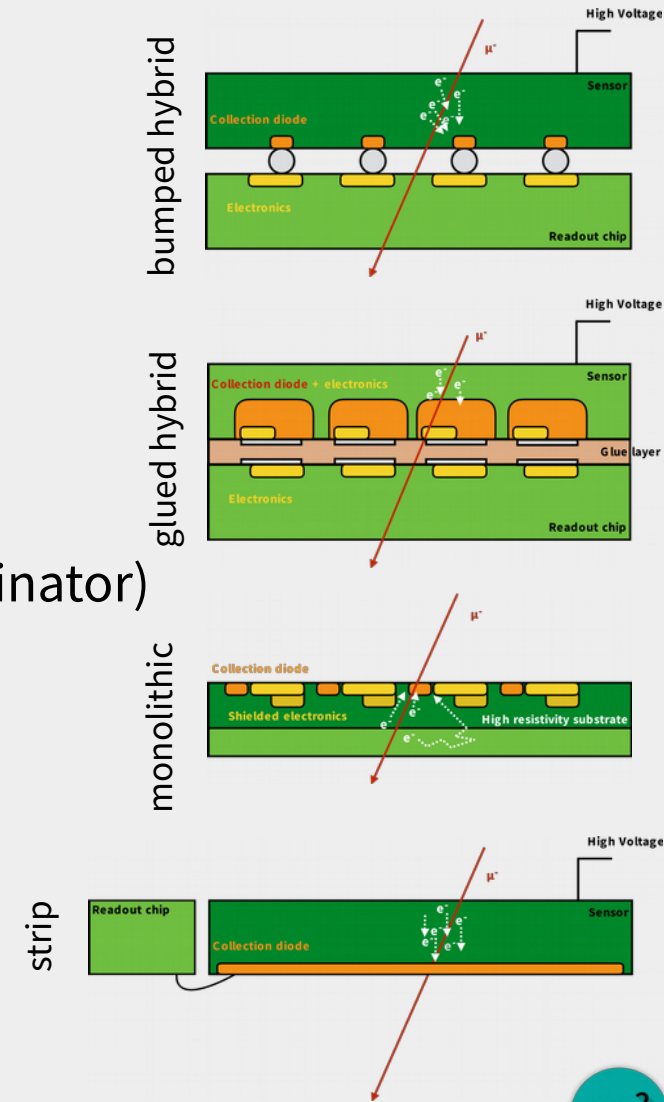
- Si sensor operated as diode in reverse bias → depleted volume
- Signal formed by motion of e/h pairs in electric field
- Contribution to motion:
 - **Diffusion** – Temperature-driven random motion, mean free path $\sim 0.1 \mu\text{m}$, mean 0
 - **Drift** – Directed motion, depending on electric field and charge carrier mobility, different parametrizations for mobility available, depending on temperature, silicon, ...
- Motion stops, when...
 - Charge carriers reach readout electrode (conductor)
 - Charge carriers recombine/get trapped (depends on purity, doping, lattice defects, ...)
- When carriers reach electrodes, total induced charge is equivalent to collected charge

Stage 3 – Signal Transfer

- Coupling between sensor & front-end can be
 - DC: bump bonds (hybrid pixel), direct (monolithic pixel)
 - AC: glue layers (hybrid pixel), SiO₂ (strip detectors)

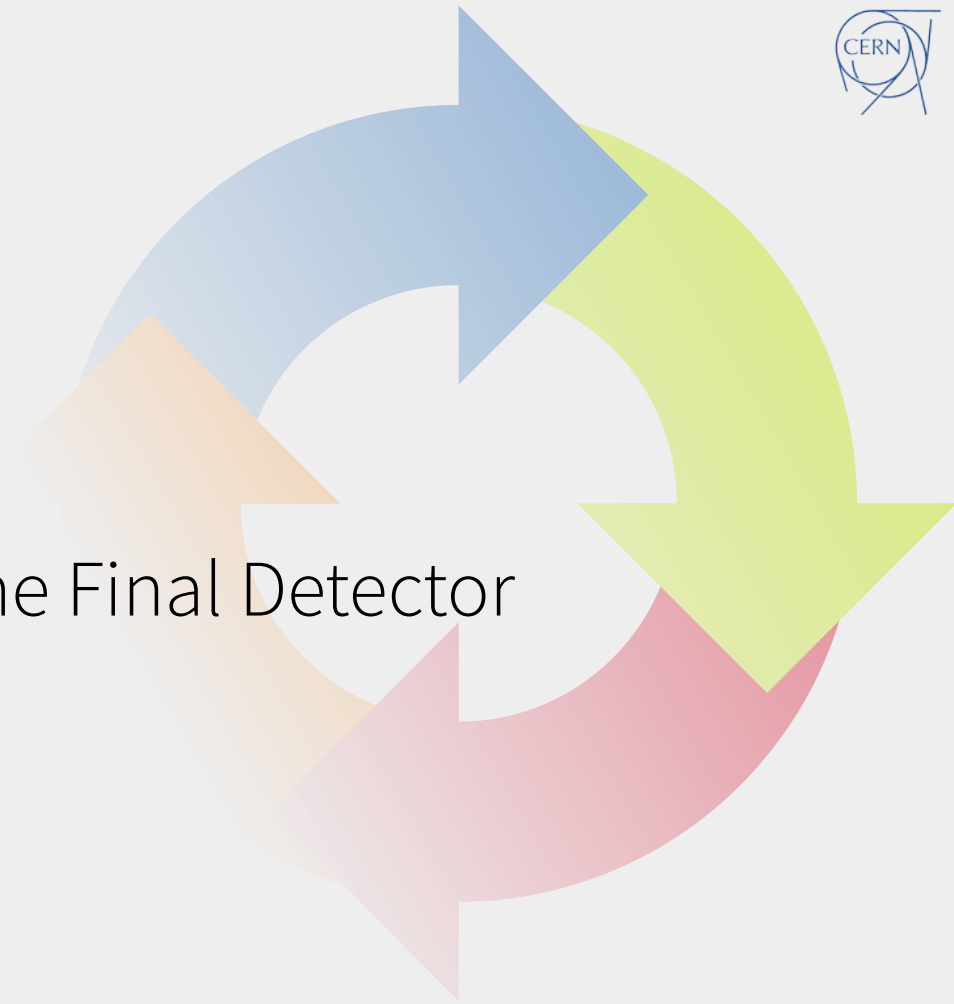
Stage 4 – Digitization

- Signal is amplified, shaped, zero-suppression (discriminator)
- Digitization of the signal via
 - Full ADC
 - Time-over -threshold
 - Threshold crossing (binary hit information)
- Buffering, encoding, data transmission...

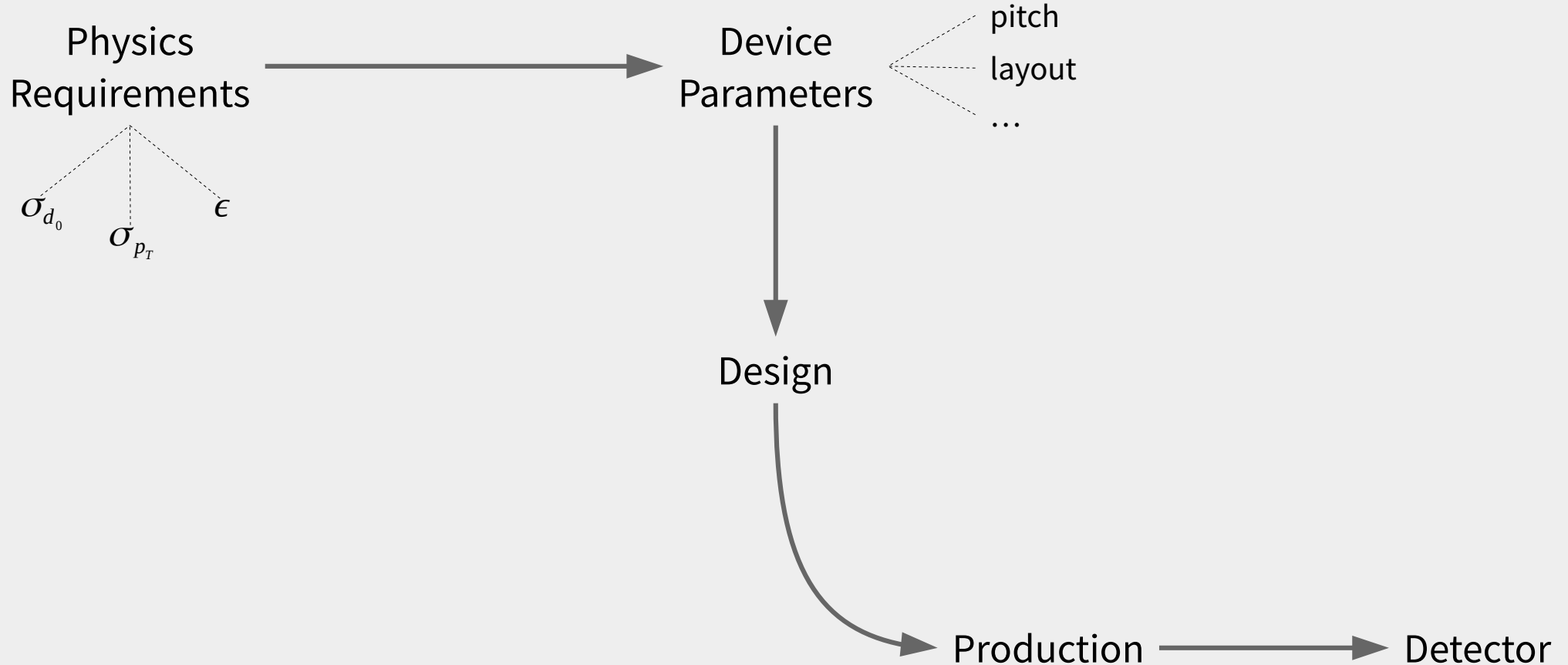


Development Cycle

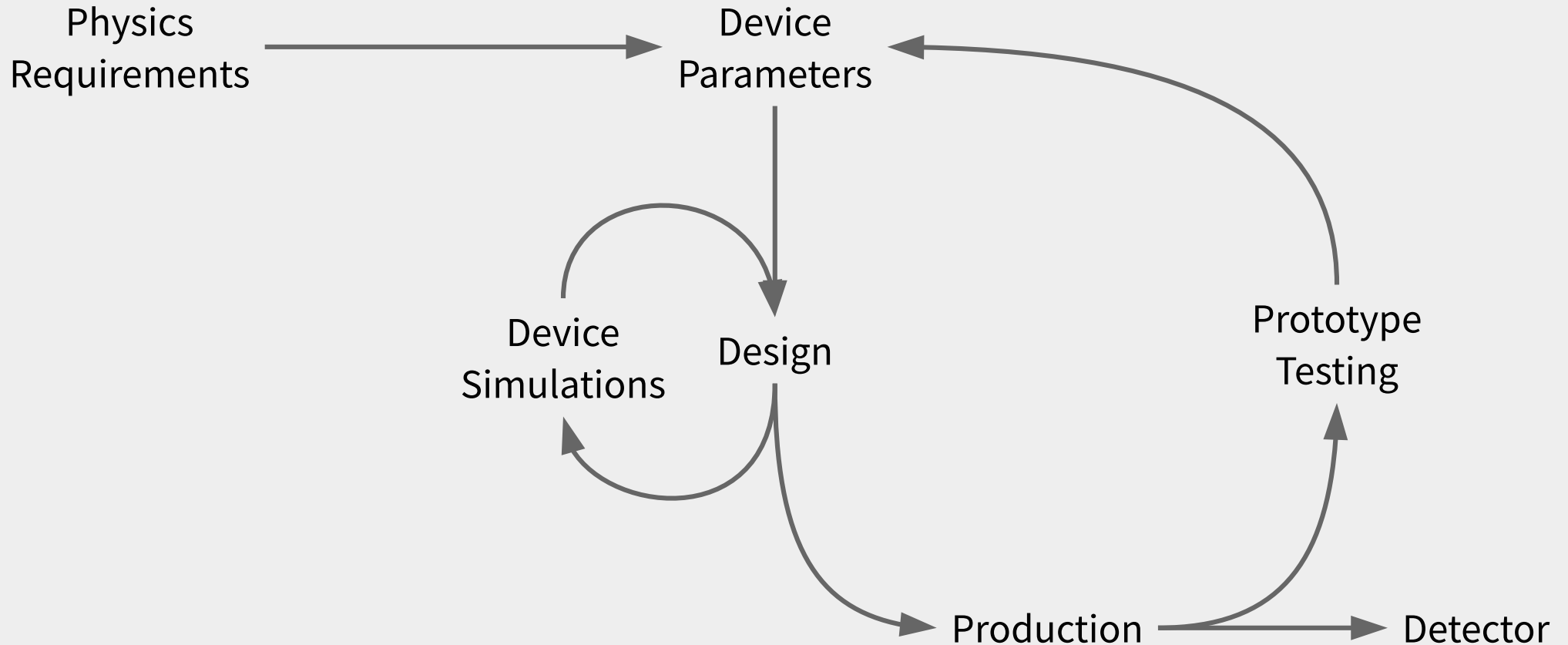
From Physics Requirements to the Final Detector



Development Cycle of a Silicon Detector

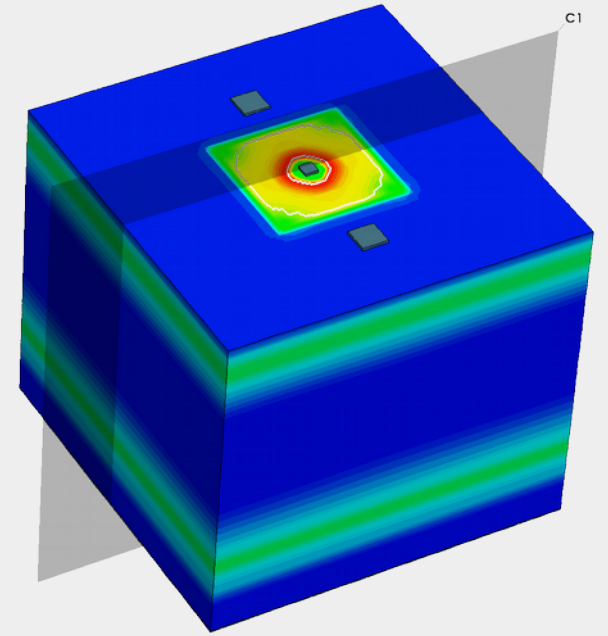


Development Cycle of a Silicon Detector



TCAD Sensor Simulations

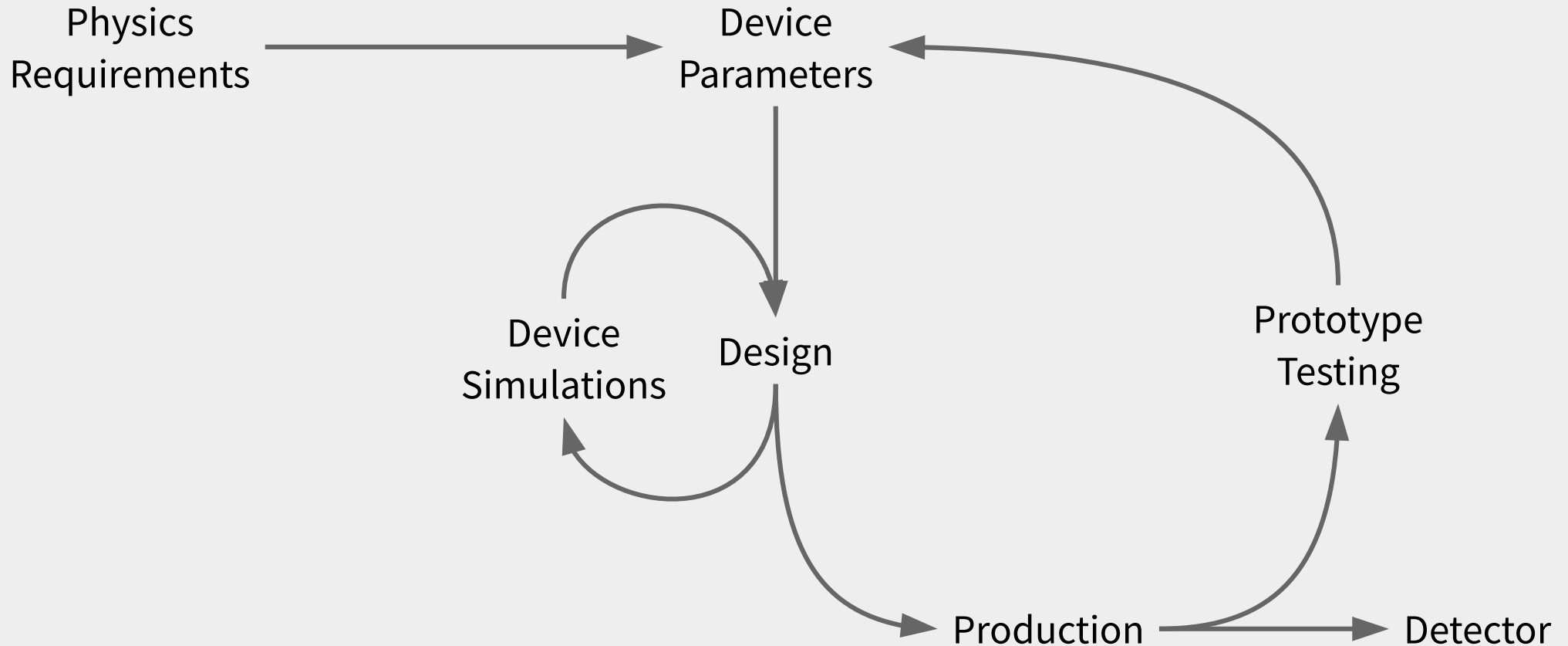
- *Technology Computer Aided Design*
 - Simulate electrical properties of semiconductor by numerically solving field equations on mesh
- Requires knowledge of the production process (doping concentrations, implants)
- Provide detailed information on
 - Field configuration of the device
 - Derived parameters: depletion voltage, break down voltage
- Also allows to perform time-resolved transient simulations: current pulses
 - Very time consuming, especially in 3D
 - Periodic boundary conditions might allow to reduce complexity



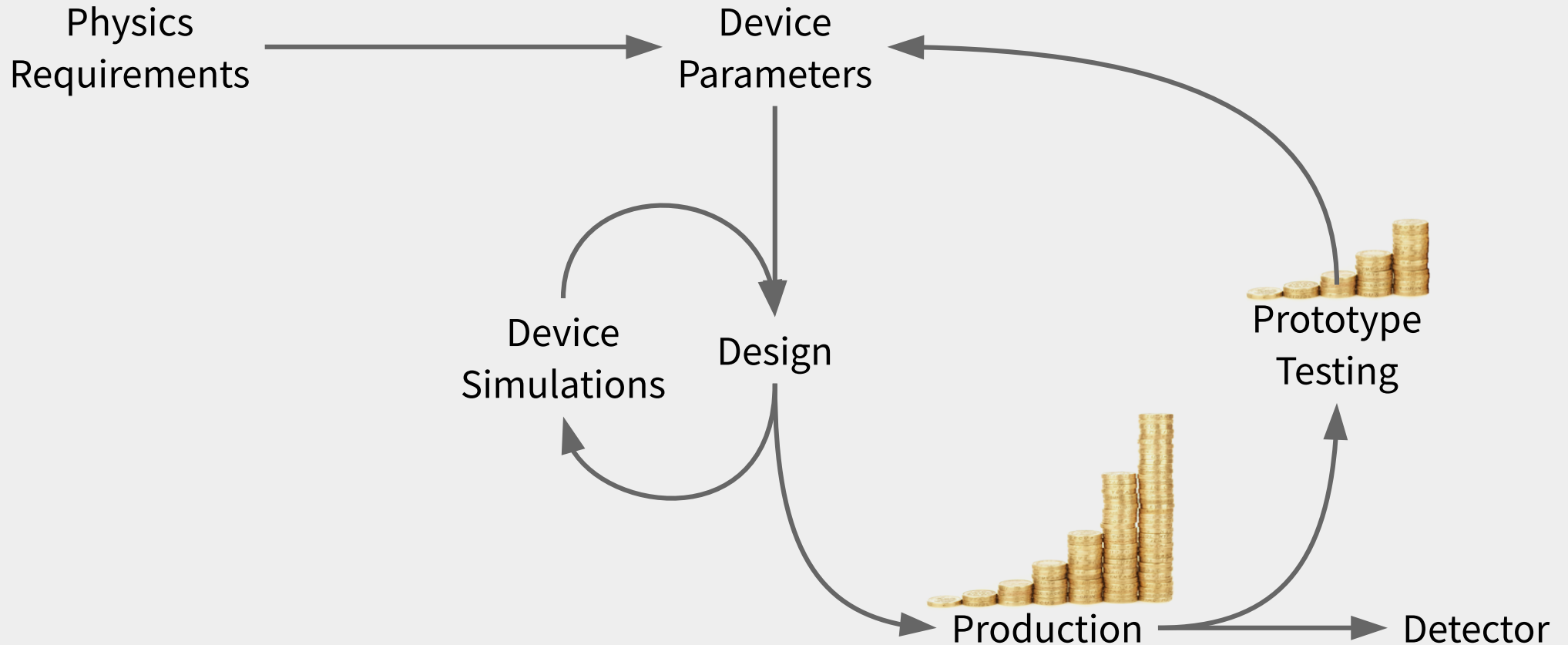
Front-End Circuit Simulation

- SPICE – *Simulation Program with Integrated Circuit Emphasis*
 - Simulate response of circuit to external stimuli
 - Many commercial derivatives, usually come with EDA software
- Based on IC design, either schematics or on netlist level
- Provides detailed information on
 - Response of front-end amplifier
 - Digitization process
- Works on individual input pulses
 - Time-consuming
 - Not really feasible to repeat for large number of input pulses

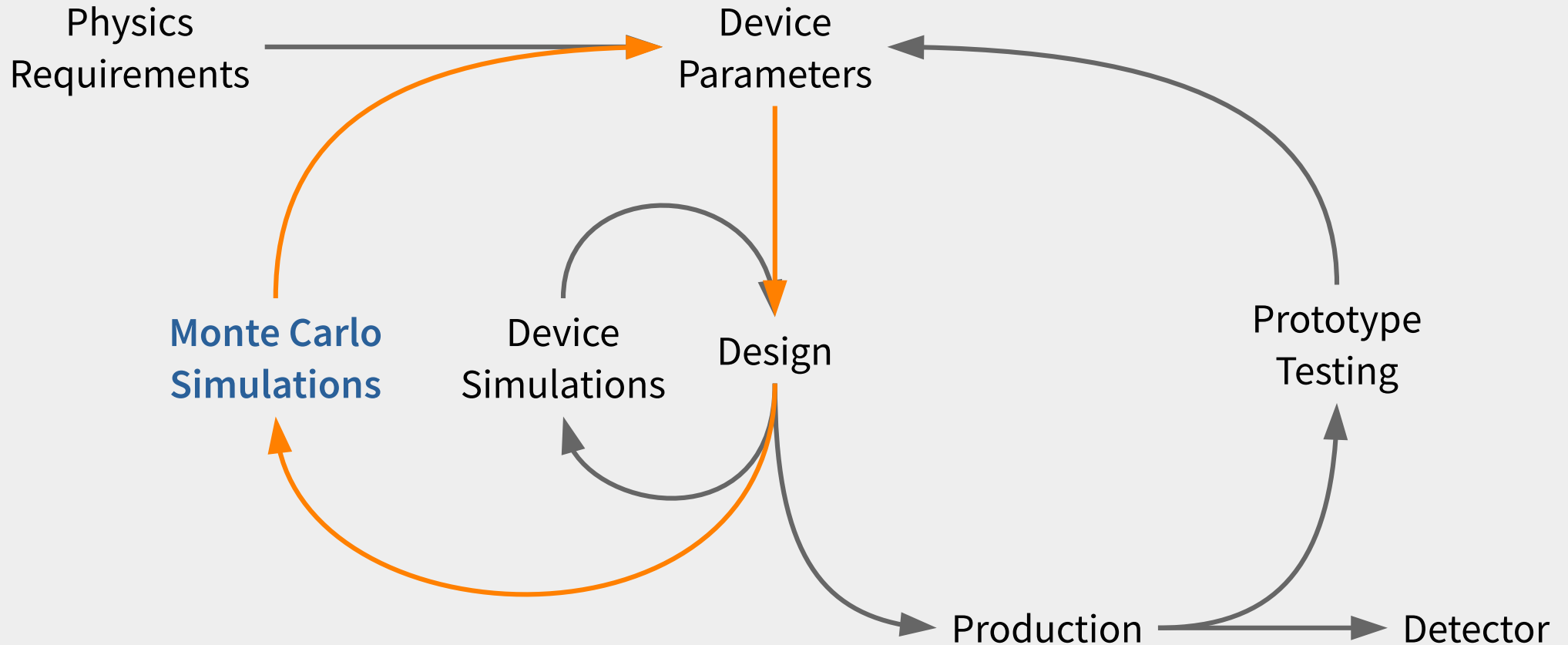
Development Cycle of a Silicon Detector



Development Cycle of a Silicon Detector

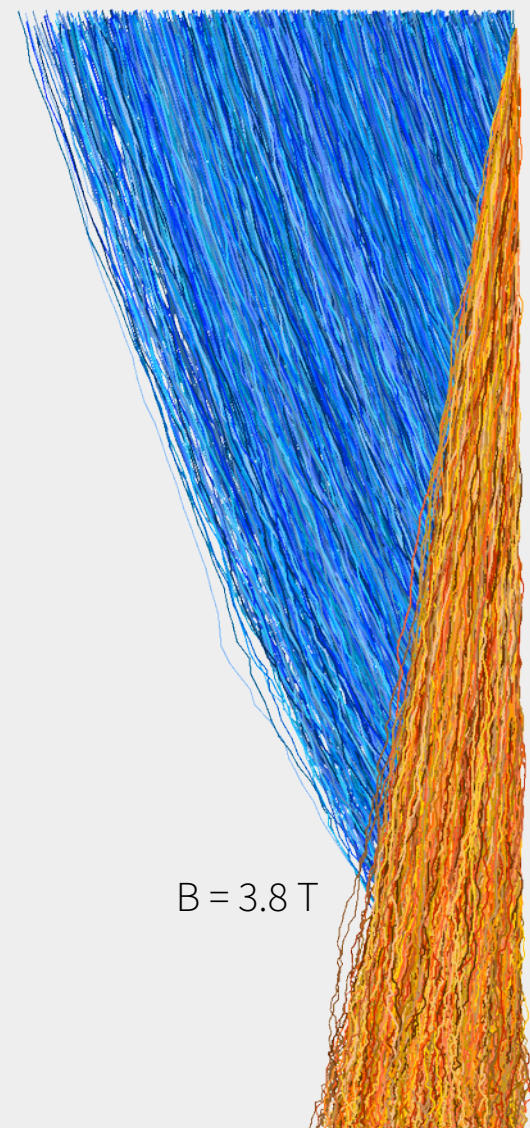


Development Cycle of a Silicon Detector



Monte Carlo Simulations

Access to Performance Parameters



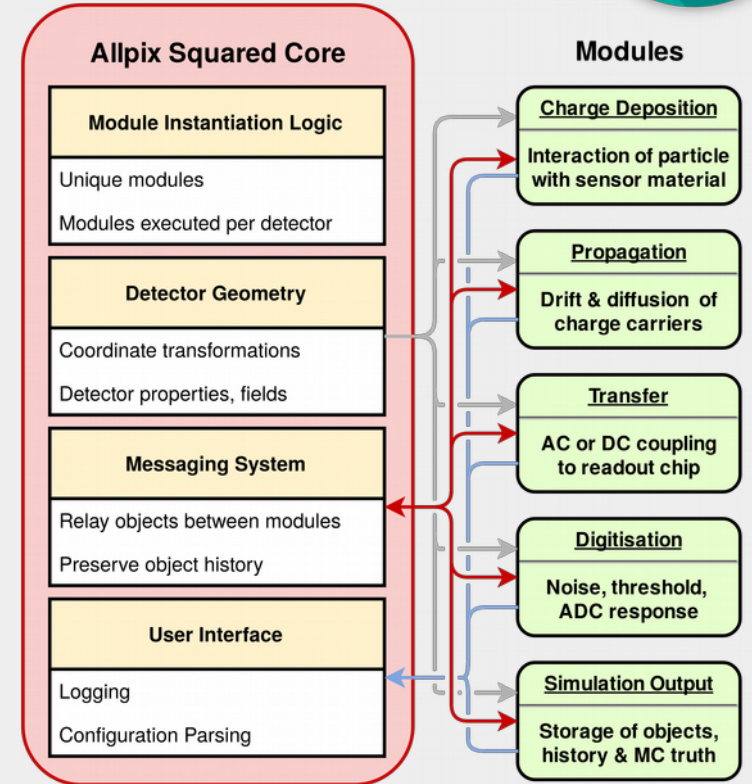
Monte Carlo Simulations

- Simulate full chain: energy deposition → readout
- Include **stochastic effects, fluctuations, secondaries**
- Requires simplifications:
 - No self-interaction, static electric field, ...
 - Empirical models for different stages
- Allows to derive performance parameters
 - Position resolution, timing, efficiency
 - Combine with results from device simulations to increase accuracy
- Monte Carlo Simulation Codes:
AllPix, PixelAV, KdetSim, (unpublished private codes), ..., **Allpix Squared**

The Allpix² Framework

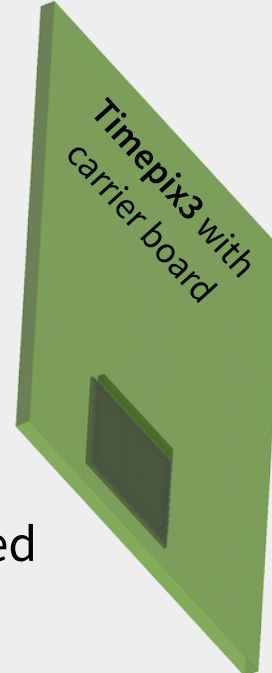


- Flexible MC simulation software, that
 - ...allows to **test different simulation models for signal formation**
 - ...implements parametrized detector models
 - ...facilitates usage of **precise electric fields**
- Focus on usability
 - Separate infrastructure from physics
 - Easy setup & configuration
 - Provide documentation (150p. [user manual](#))
- Developed within **CLICdp collaboration**



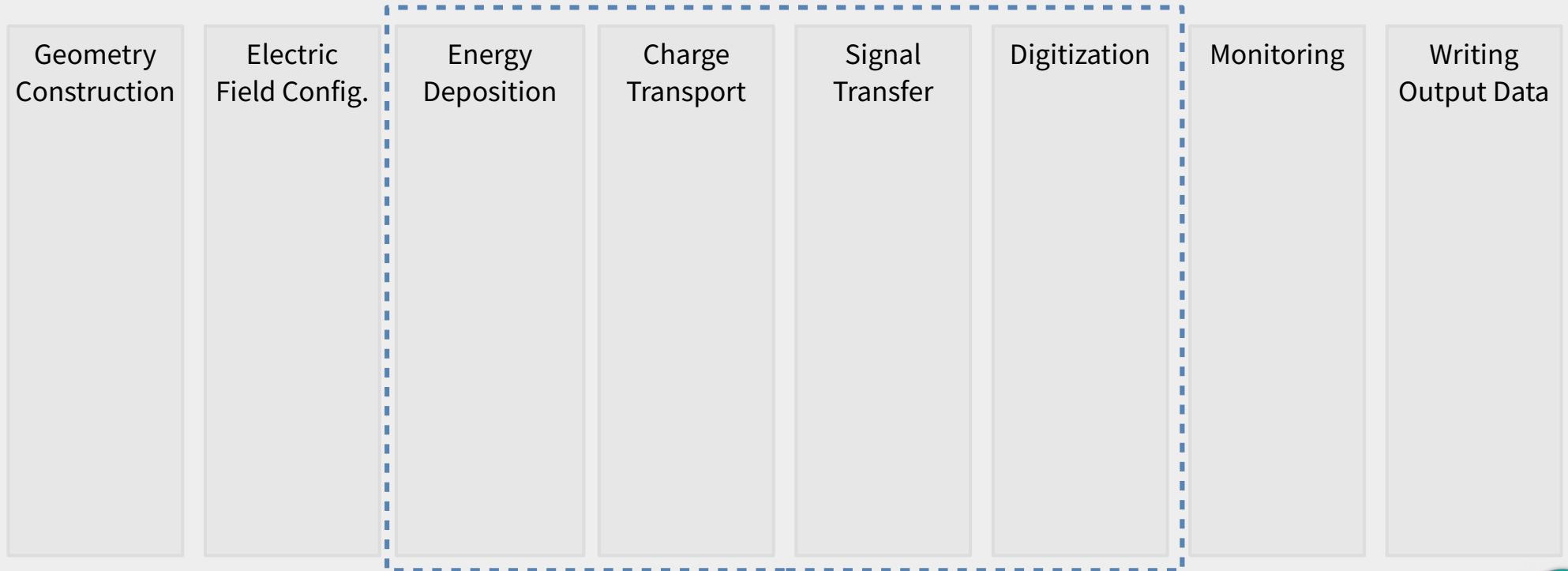
Configuration of the Simulation Chain

- Building simulation chain from individual modules
 - Configuration file with modules in order of execution
 - Support for physical units
- Every parameter documented in manual
- Geometry configuration
 - File with position/orientation of individual detectors
 - Model files define detector geometries
 - Different detector models pre-configured



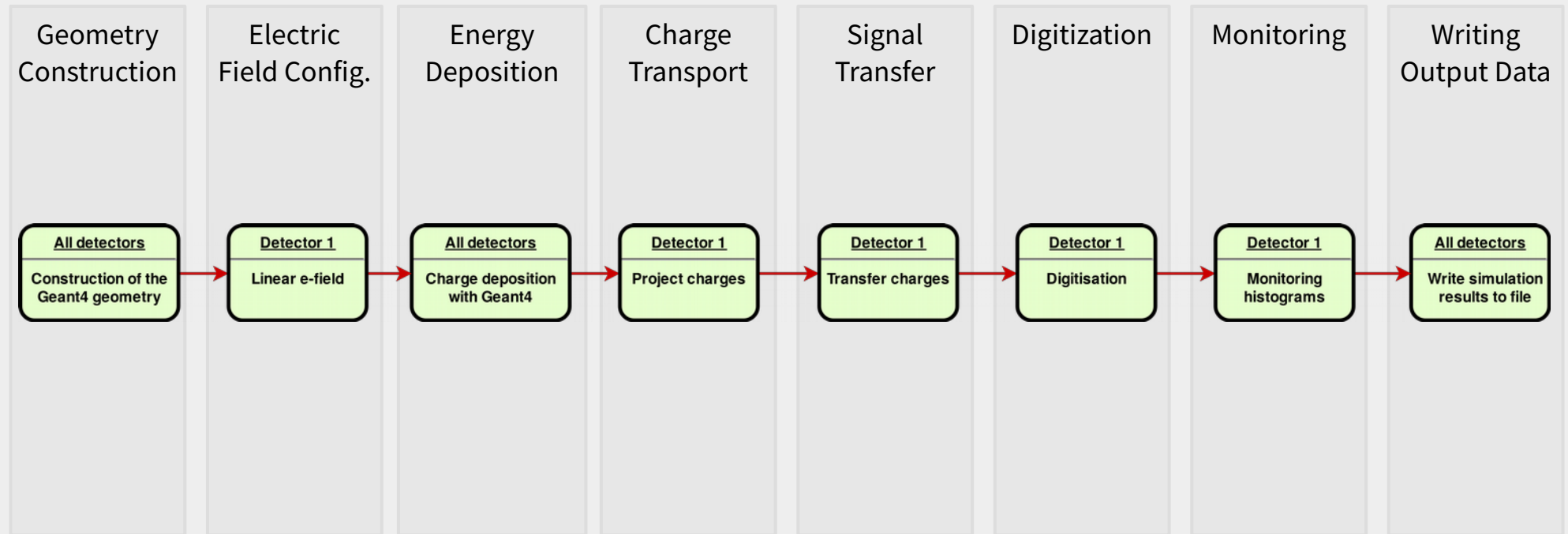
```
1 [AllPix]
2 log_level = "INFO"
3 number_of_events = 500000
4 detectors_file = "telescope.conf"
5
6 [GeometryBuilderGeant4]
7 world_material = "air"
8
9 [DepositionGeant4]
10 physics_list = FTFP_BERT_LIV
11 particle_type = "Pi+"
12 number_of_particles = 1
13 beam_energy = 120GeV
14 # ...
15
16 [ElectricFieldReader]
17 model="linear"
18 bias_voltage=150V
19 depletion_voltage=50V
20
21 [GenericPropagation]
22 temperature = 293K
23 charge_per_step = 10
24 spatial_precision = 0.0025um
25 timestep_max = 0.5ns
26
27 [SimpleTransfer]
```

The Simulation Chain



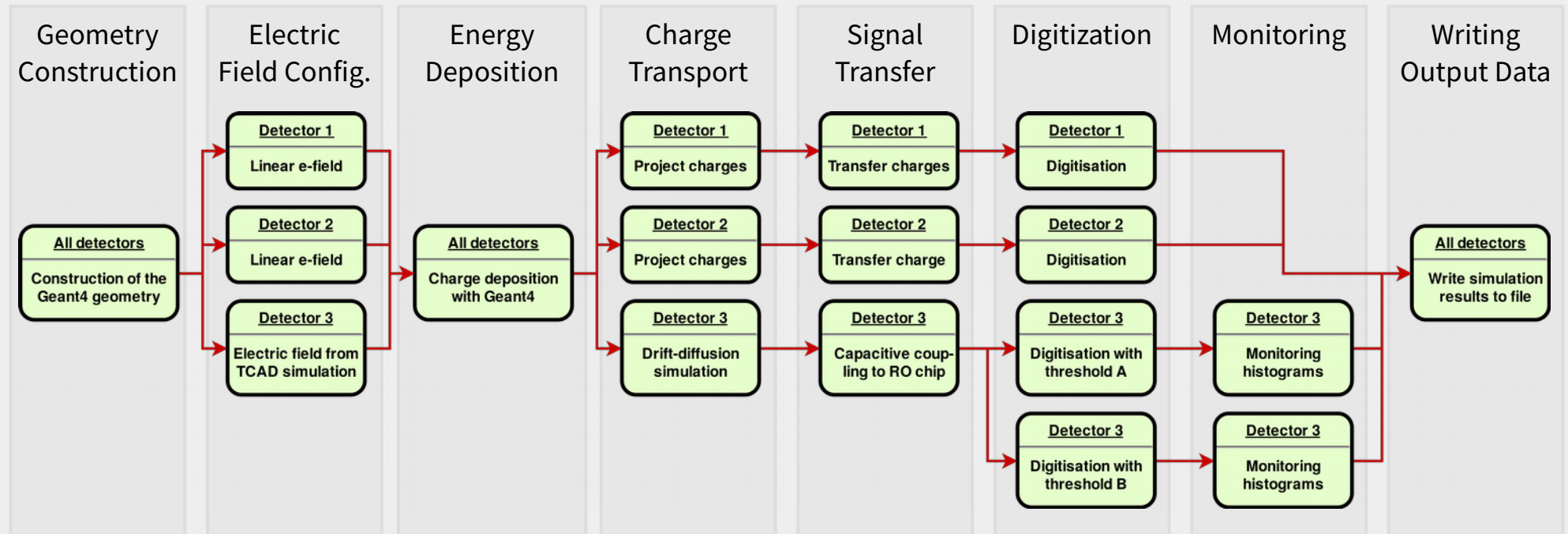
The Simulation Chain

- Building blocks follow individual steps of signal formation in detector
- Algorithms for each step can be chosen independently



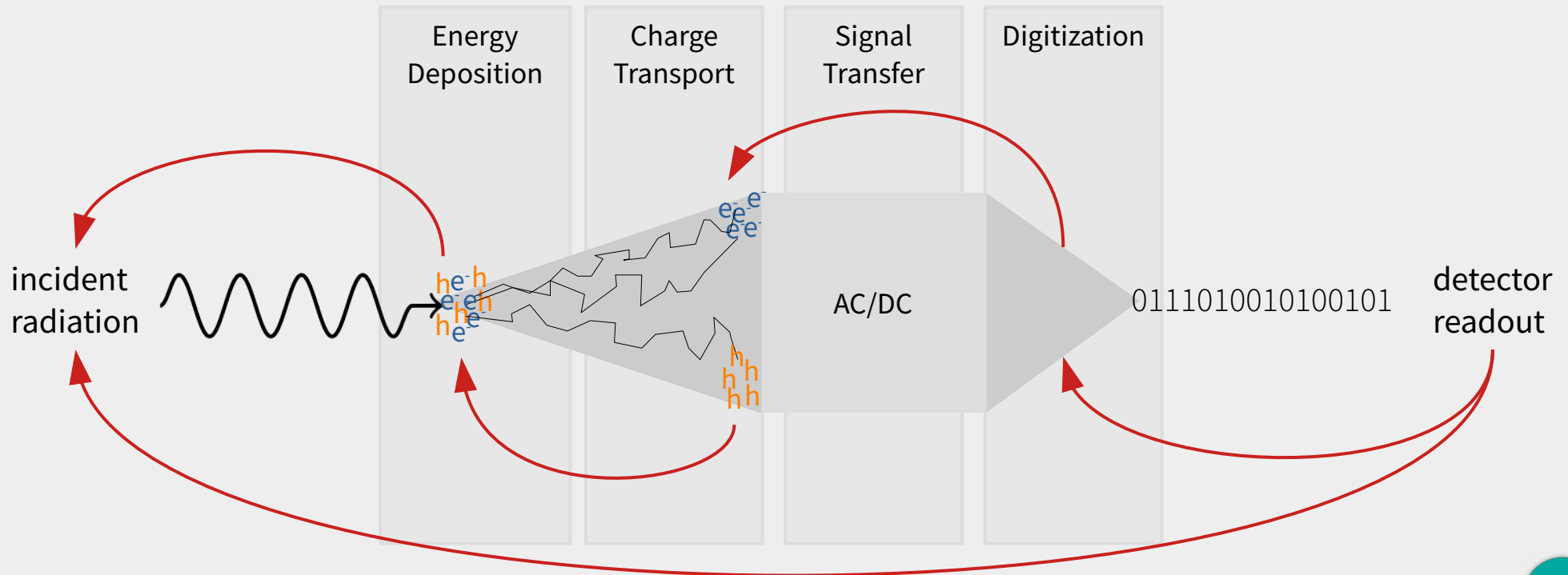
The Simulation Chain

- Simulation very flexible: modules configurable on per-detector level
- Multiple instances can be run in parallel (e.g. to simulate different front-ends)



The Monte Carlo Truth

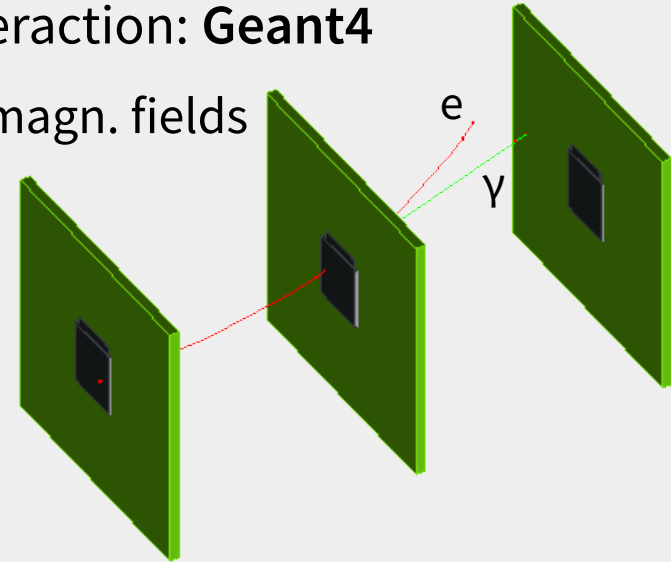
- Unlike in nature, in simulations we know everything
- Allpix² keeps history for all simulated objects – available for detailed analysis



Energy Deposition

- Using established software for simulating particle interaction: **Geant4**

- Tracking of particles through entire setup, including magn. fields
- Production and tracking of secondary particles
- Provides MC truth information on all particles
- Allows visualization of setup



- Possible alternatives:

- Very simple model: Depositing charge at single point or along line
- Custom code using energy loss spectra and lookup tables delta ray ranges
- Custom code for simulation of laser measurements

Charge Transport

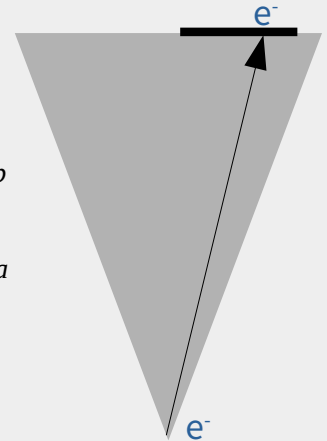
- Most crucial (and time consuming) component in simulation chain
- Various models with different complexity:
 - $O(1)$ – Projecting Charge Carriers
 - $O(N)$ – Integration of Equations of Motion
 - $O(2 \times N \times M)$ – Induced Signal at Electrodes
- Multiple charge carriers from same energy deposit propagated together
 - Depending on initial statistics and required accuracy
 - Some models allow to ignore electrons or holes
- Computing time given per group of charge carriers

O(1) – Projecting Charge Carriers

- With linear electric field, calculate approximate total drift time via analytical approximation of mobility integral
- For each (group of) charge carrier,
 - Calculate total drift time
 - Calculate total diffusion offset for this time
 - Put charge carrier on sensor surface, with offset drawn from Gaussian distribution of width σ_x
- Very fast simulation, few calculations
- Only works for linear electric field approximations (reasonable for many thick planar sensors) and without magnetic field

$$t = \int \frac{1}{v} ds \approx \frac{1}{\mu_0} \left[\frac{\ln(E(s))}{k} + \frac{s}{E_c} \right]_a^b$$

$$E(s) = ks + E_0$$

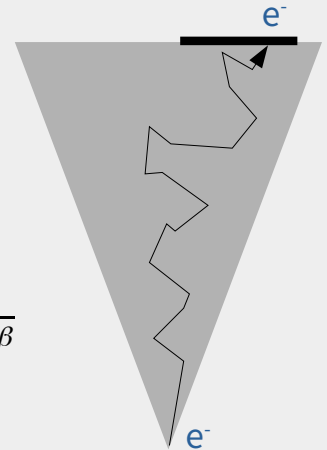


O(N) – Integration of Equations of Motion

- Successive integration of charge carrier motion
- Take each (group of) charge carrier
 - Calculate mobility μ from local electric (and magnetic) field (using Jacoboni/Canali parametrization)
 - Calculate velocity
 - Make step, add diffusion offset from Gaussian distribution
 - Repeat N times until sensor surface is reached
- Using 5th order Runge-Kutta-Fehlberg method
 - Adaptive step size according to position uncertainty
 - Method allows description of drift in complex field configurations

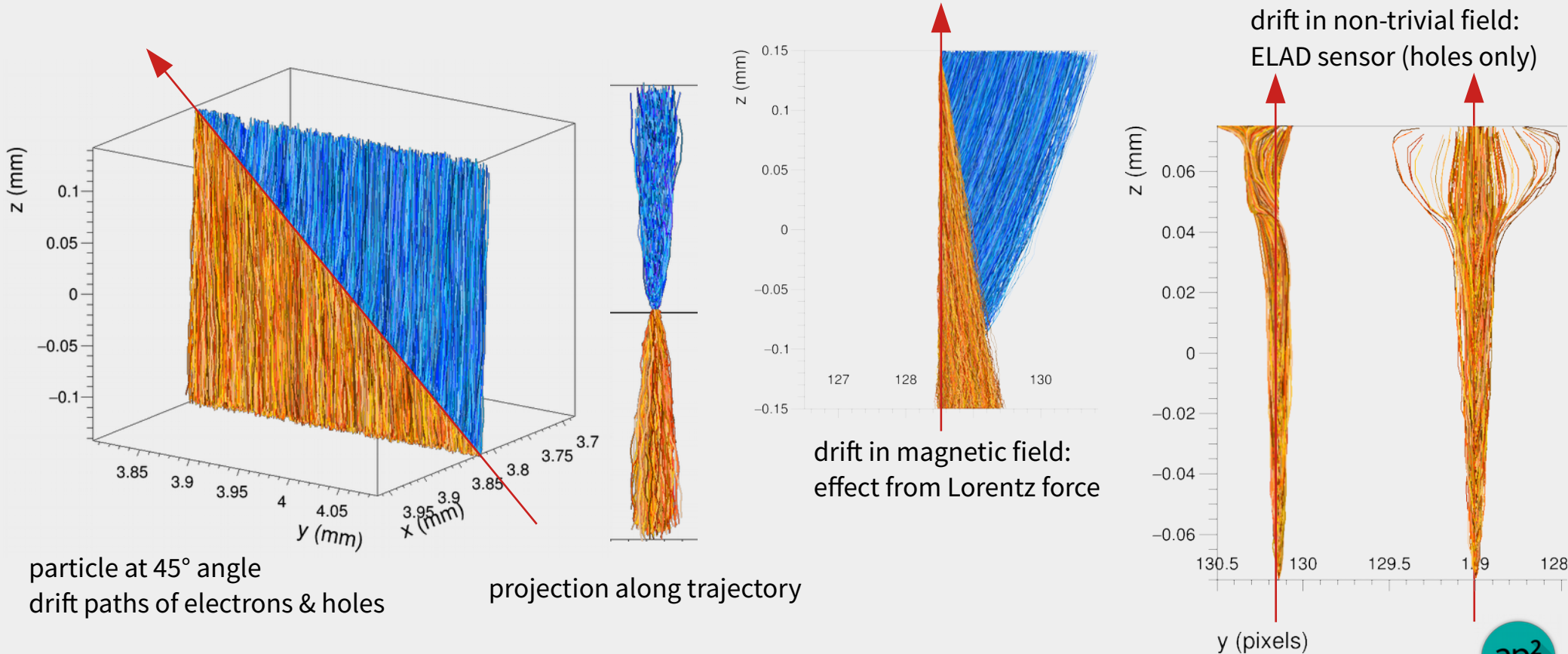
$$\mu = \frac{v_m}{E_c} \frac{1}{(1 + (E/E_c)^\beta)^{1/\beta}}$$

$$\sigma_x = \sqrt{\frac{2k_b T}{e} \mu t}$$



Drift Path Visualizations

Recording individual steps of the RKF integration to produce visualizations



particle at 45° angle
drift paths of electrons & holes

projection along trajectory

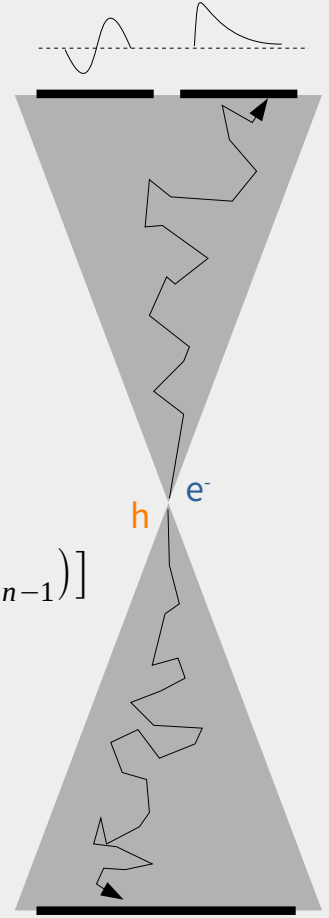
drift in magnetic field:
effect from Lorentz force

drift in non-trivial field:
ELAD sensor (holes only)

O(2xNxM) – Induced Signal at Electrodes

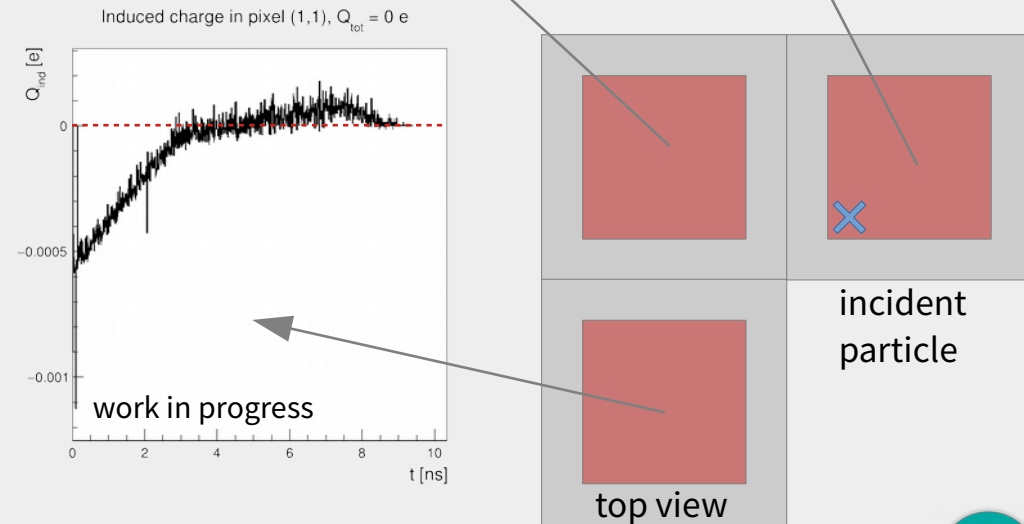
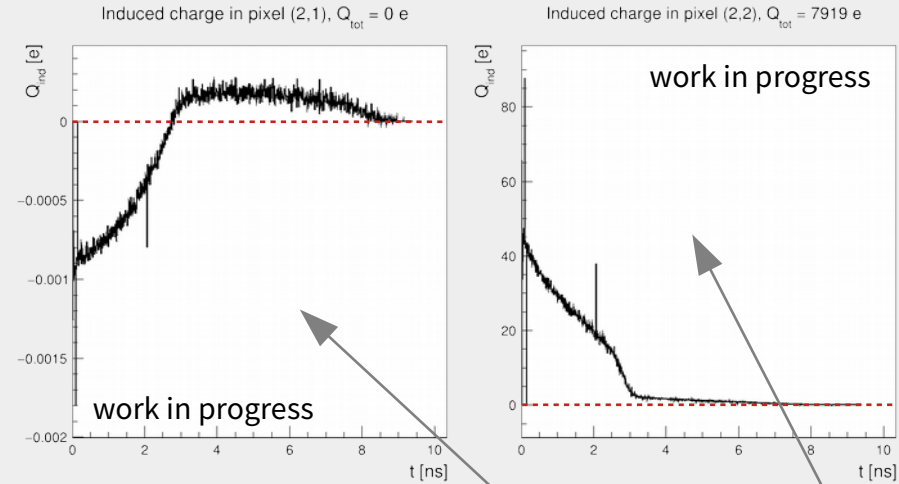
- Successive integration of motion, calculating induced charge per step
- Take each (group of) charge carrier
 - Calculate mobility & velocity from local fields
 - Make step, add diffusion offset from Gaussian distribution
 - Get induced charge from weighting potential difference for M neighbors
 - Repeat N times until sensor surface is reached
- Allows time-resolved simulation
 - Requires weighting potential, might not be trivial to obtain
- Time consuming:
 - Calculation for all neighboring electrodes for every step
 - Requires propagating both electrons and holes (x2)

$$Q_n^{ind.} = \int_{t_{n-1}}^{t_n} I_n^{ind.} dt = q [\phi(x_n) - \phi(x_{n-1})]$$



Current Pulses at Electrodes

- Example of transient simulation
Disclaimer: work in progress
- Detector with
 - 300 μm x 300 μm pitch,
200 μm x 200 μm electrodes,
100 μm sensor thickness
 - MIP-equiv. Particle,
80 e/h-pairs / μm
- Struck pixel sees total charge
- Neighbor pixels see tiny pulses,
net charge is zero

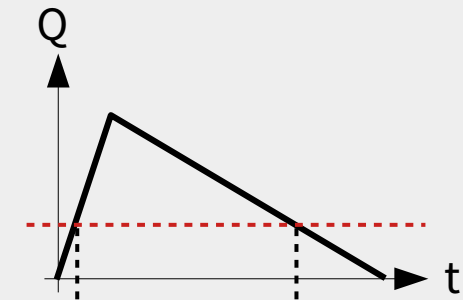
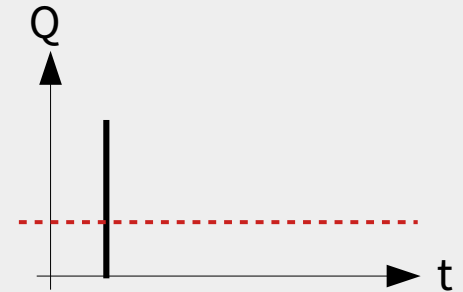


Including Additional Effects

- Depending on simulation scenario, additional effects might be required
 - Slow sensors might expose effects from recombination
 - Irradiated sensors see strong effect from trapping
- Some can be added ad-hoc to propagation models:
 - Trapping of carriers (stop propagation for certain time)
 - Recombination (stop propagation completely)
 - Multiplication (create new charge carriers at strong electric fields)
- Other effects (shielding effects in electric field, charge carrier self-interaction) are more difficult to include, complexity might go beyond MC simulations

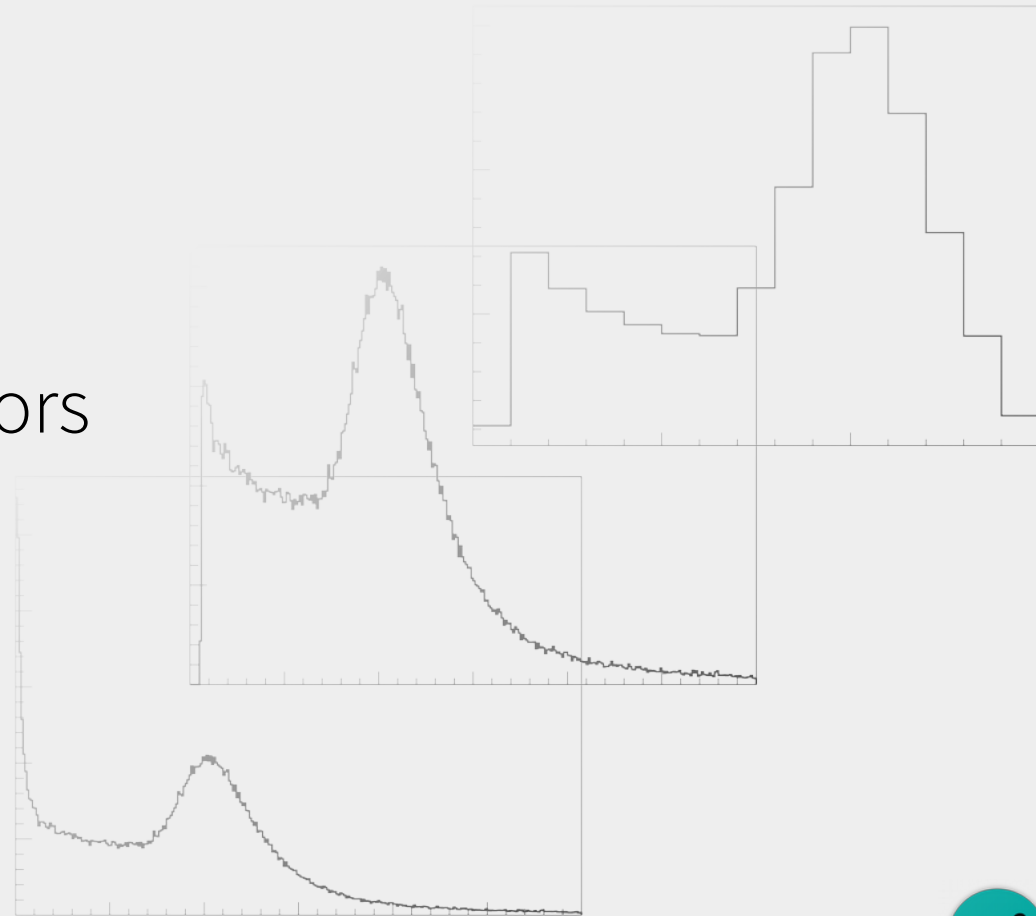
Digitization

- Methods depend on available information from charge transport:
- Simple front-end
 - Compare total charge against configured threshold
 - Add input noise, threshold dispersion, convert to ADC units
- Front-end with timing capabilities
 - Requires current pulse
 - Threshold crossings for time-of-arrival and time-over-threshold
- Full front-end simulation
 - Requires current pulse shape
 - Lookup tables for front-end response function, produced from device simulations



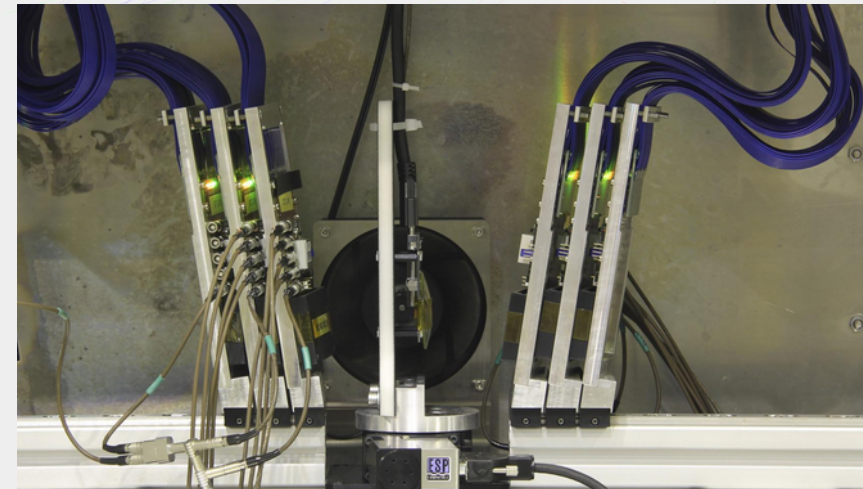
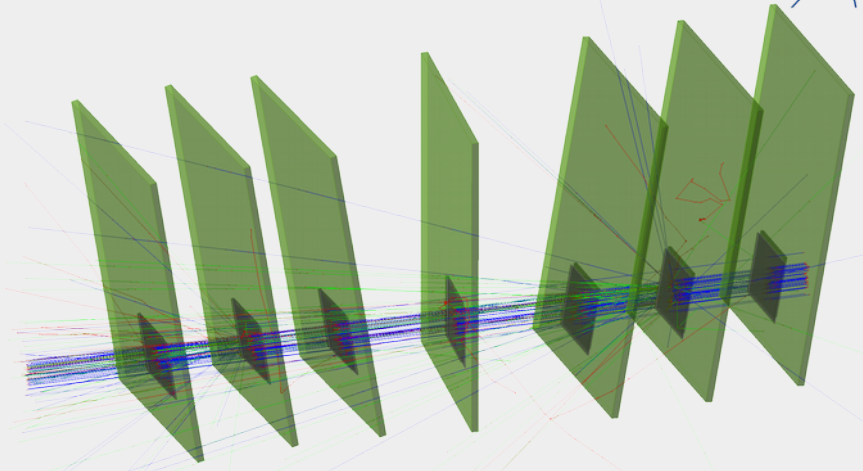
Examples

Planar, ELAD and CMOS Sensors



Simulation of Detector System

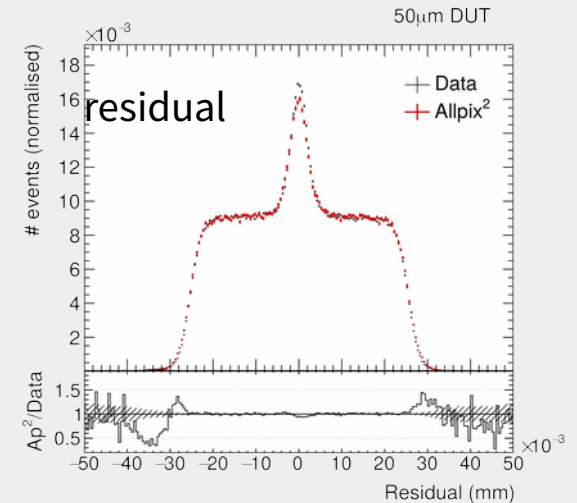
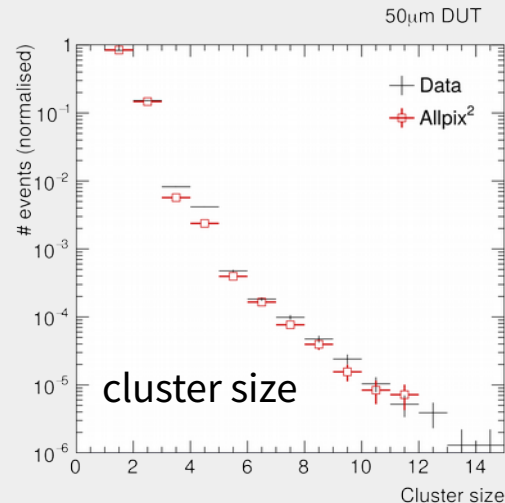
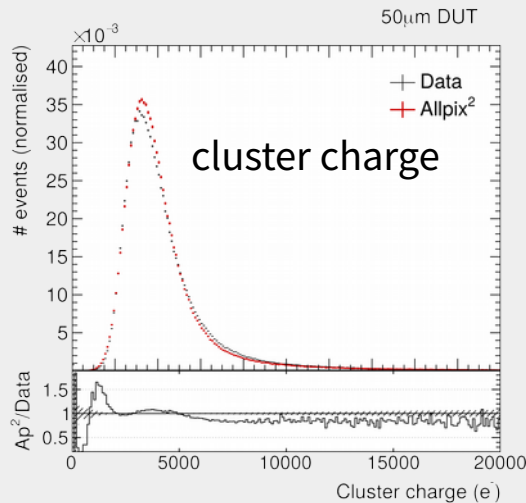
- Simulation of a beam telescope setup:
CLICdp Timepix3 telescope @ SPS H6
 - Telescope: 6x Timepix3 w/ 300 μm sensors
 - DUT: 1x Timepix3 w/ 50 μm sensor
- Validation of reconstruction
- Different algorithms used:
 - Telescope: projection
 - DUT: successive integration
- Linear electric field approximation



NIMA 901 (2018) 164 – 172
[doi:10.1016/j.nima.2018.06.020](https://doi.org/10.1016/j.nima.2018.06.020)

Simulation of Detector System

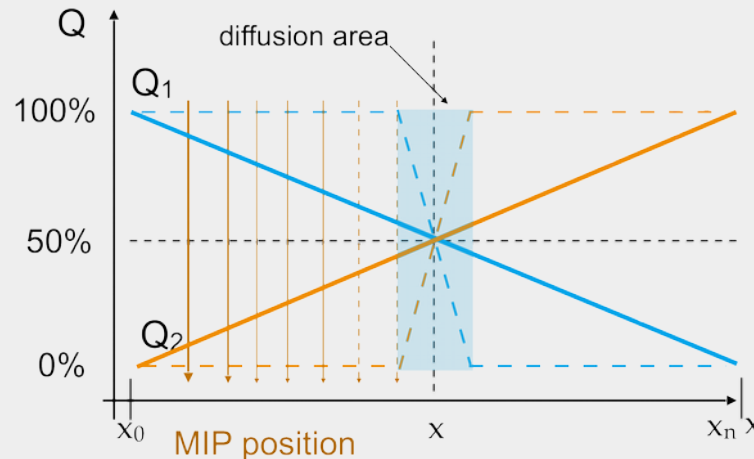
- Using same reconstruction algorithms as for data: clustering, η correction, tracking
- Very good agreement between data and simulation observed (total charge: **Geant4**; cluster size: both; residual shape: **Allpix²**)



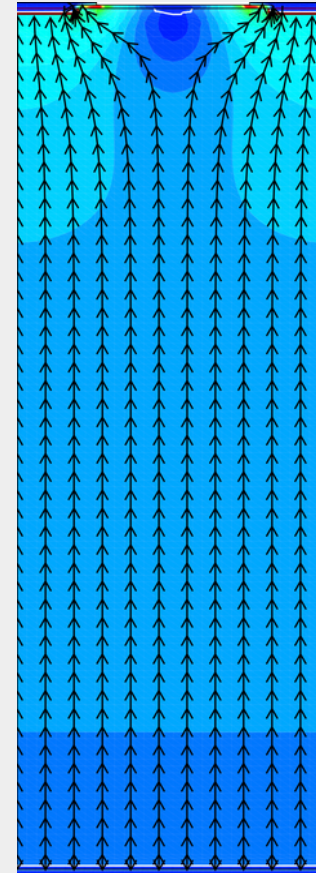
Enhanced Lateral Drift Sensors

- Resolution in **thin sensors** limited to $\text{pitch} / \sqrt{12}$
- **Enhance charge sharing** via electric field
 - Deep implants create lateral field
 - Spread of charges during drift, cluster size ~ 2
- Theoretical optimum: linear sharing

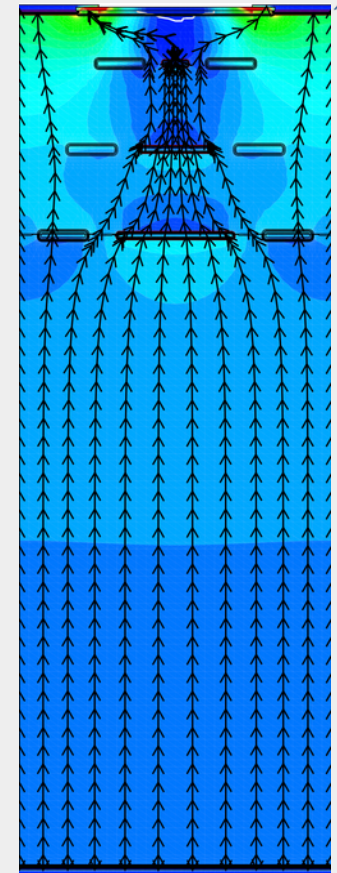
- No prototype yet:
use simulation to optimize sensor



standard planar



p-ELAD



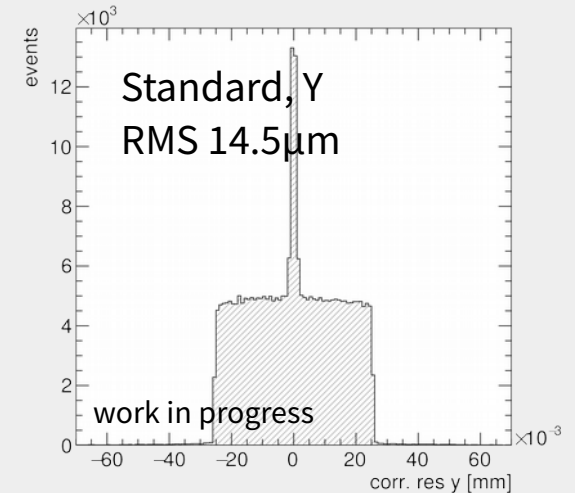
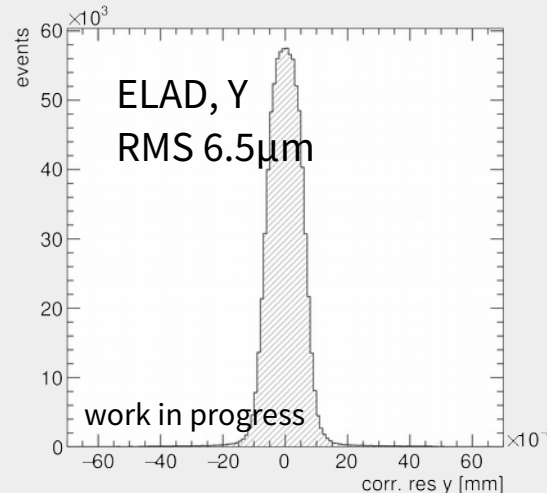
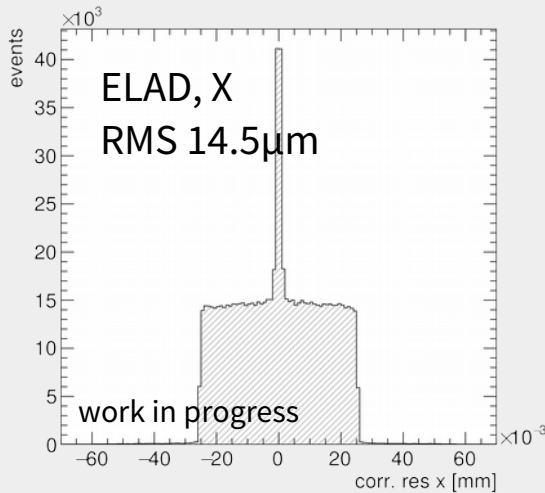
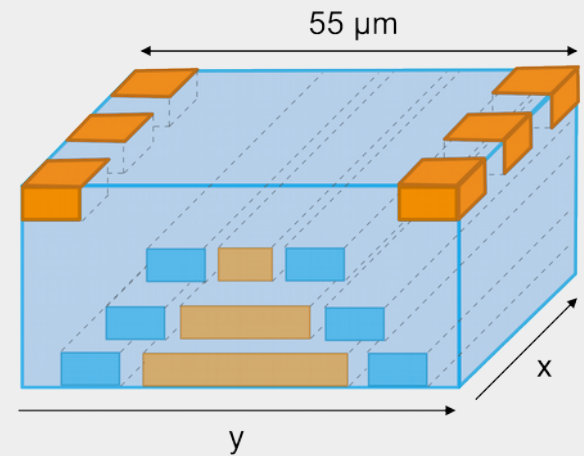
NIMA 831 (2016) 242 – 245
[doi:10.1016/j.nima.2016.01.092](https://doi.org/10.1016/j.nima.2016.01.092)



Enhanced Lateral Drift Sensors

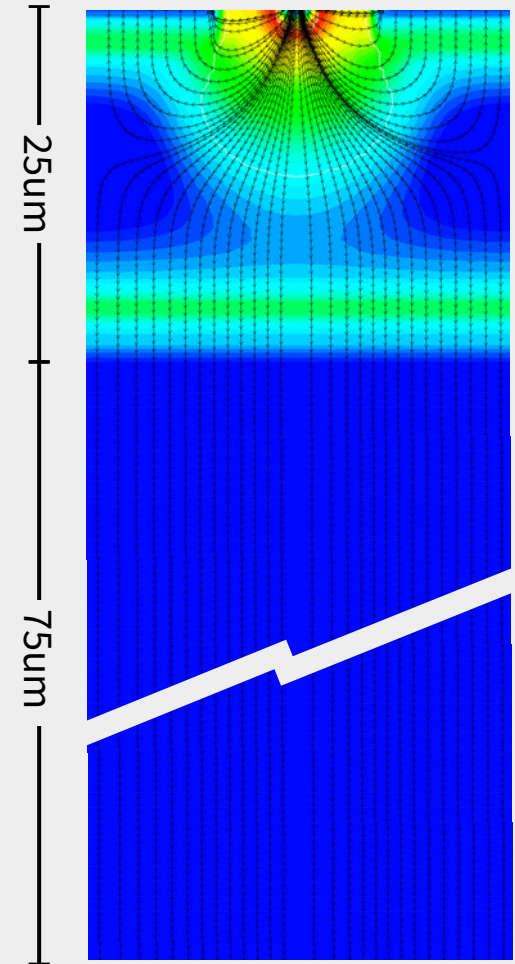


- MC Simulation with Timepix3 pitch: $55\ \mu\text{m}$
- Strip-like ELAD implants, expecting
 - X: Unaffected charge sharing along strip implants
 - Y: Stronger charge sharing across strip implants
- Using TCAD electric field & successive integration model



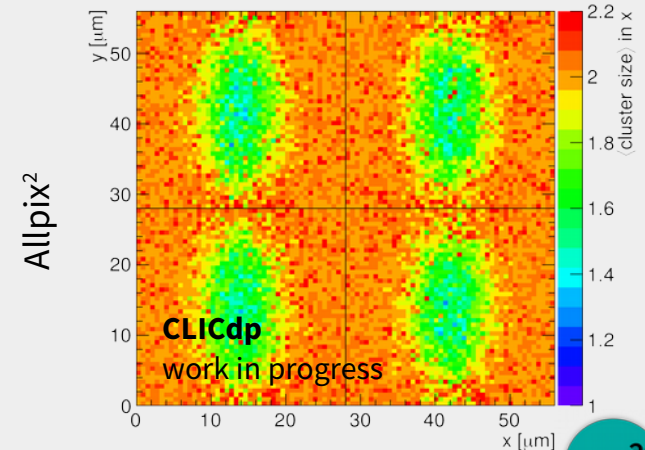
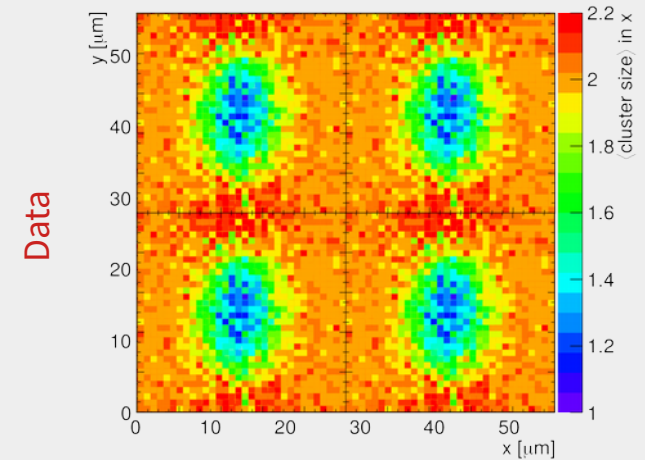
Monolithic CMOS in High-Resistivity Silicon

- ALICE Investigator chip, pixels with 28x28um pitch
 - Field in top 25um (high-resistivity) silicon
 - Undepleted in 75um silicon substrate
 - Measurements published: [doi:10.1016/j.nima.2019.02.049](https://doi.org/10.1016/j.nima.2019.02.049) NIMA 927 (2019) 187-193
- Simulation compared to data from SPS, 120 GeV π
 - Simulating only detector under investigation
 - Using Monte Carlo truth information as reference
 - Smearing with telescope resolution obtained from data
- Electrostatic field obtained from TCAD simulations



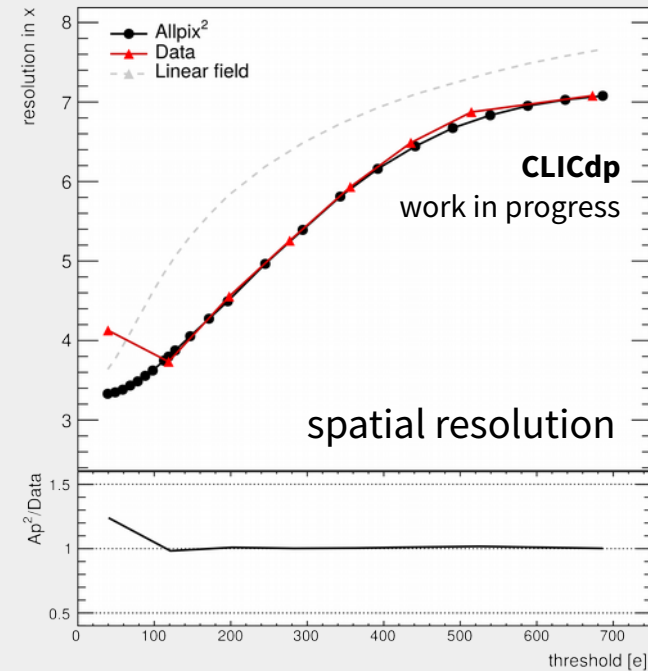
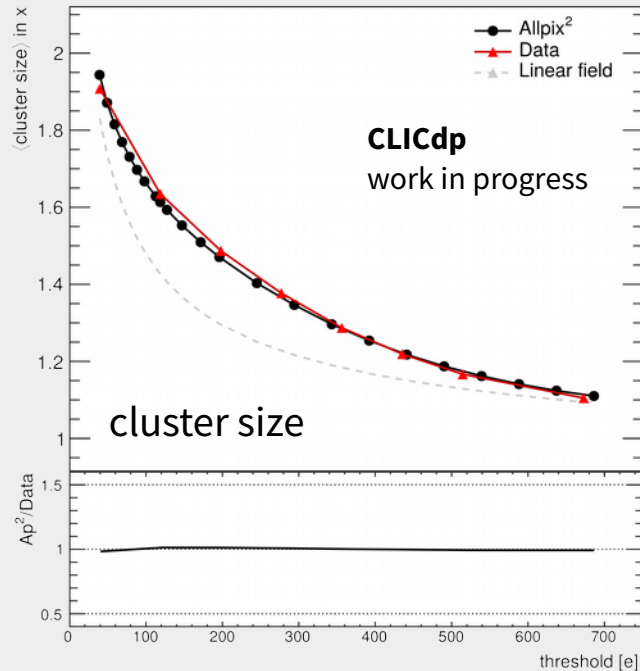
Monolithic CMOS in High-Resistivity Silicon

- High statistics of 3D Monte Carlo simulation:
 - Sampling of quantities within pixel cells
 - Here: cluster size in x
- Fully depleted planar sensors: expecting bands without y-dependence
- Cluster size exhibits correlation between x/y
 - Reason is field configuration & signal contributions from diffusion
 - Simulation with TCAD electric field reproduces correlation



Monolithic CMOS in High-Resistivity Silicon

- Data and simulation match well, e.g. for **cluster size & resolution vs. threshold**
- Simulation with linear electric field does not describe data



In a nutshell...



A Word on Writing Code for MC Simulations

- Implementation of algorithms is not the most time-consuming part
- Most time-consuming part is to do it such, that the algorithms are...
 - ...validated with prototype data & device simulations
 - ...well documented
 - ...maintainable over a longer period than O(1 fellow) / O(1 PhD)
- Development of Allpix²: spend considerable time on
 - Writing documentation → lower barrier for new users
 - Implementing automated testing, compilation → ensure software always works
 - Code review for new features → ensure functionality/compatibility

Allpix² Users, Contributors



- First **user workshop** held
26-27 November 2018 @ CERN
Tutorials, discussions, feedback
- Increasing number of community contributions to the code base

ONERA Aerospace Lab, Toulouse

Georg-August-Universität Göttingen

University of Birmingham

University of California, Berkeley

NIKHEF, Amsterdam University of Glasgow

Czech Techn. University, Prague

Rutherford Lab, STFC

ETH Zurich

IHEP Beijing

Université de Montréal Charles University, Prague

CLICdp @ CERN

CMS Pixel @ CERN

ATLAS Strips @ CERN

LHCb VeloPix @ CERN

ATLAS Monolithic @ CERN

Freiburg University

Utrecht University

ATLAS @ DESY

CMS Lorentz Angle @ DESY

ELAD @ DESY

University of Liverpool

ATLAS SCT @ KEK

Dortmund University

Université de Genève

AGH University Krakau

Disclaimer: these are just some user groups we have been in contact with...

Summary

- Designing a new silicon detector is a major undertaking
- Simulations are a vital component of the prototyping effort
 - Device simulations help in understanding and optimizing the design
 - Monte Carlo Simulations are required to assess the device performance
- Models with different complexity are available
 - fast & coarse ↔ slow & precise
- Including results from device simulations improves detector modeling
- **Allpix Squared**: flexible platform for implementation of different algorithms
- Extensions planned, participation from community very welcome

Allpix Squared Resources



Website

<https://cern.ch/allpix-squared>



Repository

<https://gitlab.cern.ch/allpix-squared/allpix-squared>



Docker Images

https://gitlab.cern.ch/allpix-squared/allpix-squared/container_registry



User Forum:

<https://cern.ch/allpix-squared-forum/>



Mailing Lists:

allpix-squared-users <https://e-groups.cern.ch/e-groups/Egroup.do?egroupId=10262858>

allpix-squared-developers <https://e-groups.cern.ch/e-groups/Egroup.do?egroupId=10273730>



User Manual:

<https://cern.ch/allpix-squared/usermanual/allpix-manual.pdf>

